

Refine Search

Search Results -

Term	Documents
(8 AND 17).PGPB,USPT.	2
(L8 AND L17).PGPB,USPT.	2

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Search:

L19

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side by side			
<i>DB=PGPB,USPT; PLUR=YES; OP=OR</i>			
<u>L19</u>	l8 and l17	2	<u>L19</u>
<u>L18</u>	l8 and L16	0	<u>L18</u>
<u>L17</u>	(713/401-601)[CCLS]	3050	<u>L17</u>
<u>L16</u>	(714/15)[CCLS]	566	<u>L16</u>
<u>L15</u>	(714/15)![CCLS]	2	<u>L15</u>
<u>L14</u>	l9 and l4	2851	<u>L14</u>
<u>L13</u>	l10 and l4	132	<u>L13</u>
<u>L12</u>	(l10 and l4)[CCLS]	0	<u>L12</u>
<u>L11</u>	(l10 and l4)![CCLS]	0	<u>L11</u>
<u>L10</u>	(710/261-266)![CCLS]	805	<u>L10</u>
<u>L9</u>	(712/2-300)[CCLS]	10878	<u>L9</u>
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>			

<u>L8</u>	L7 and l2	103	<u>L8</u>
<u>L7</u>	l3 near25 l4	586	<u>L7</u>
<u>L6</u>	L5 and l4	2083	<u>L6</u>
<u>L5</u>	L2 and l3	5997	<u>L5</u>
	(activat\$4 or inactivat\$4 or inhibit\$4 or disabl\$4 or enabl\$4 or hold\$4 or		
<u>L4</u>	held) near8 (memor\$4 or stor\$4 or eprom or eeprom or rom or ram) near10	49792	<u>L4</u>
	(program\$1 or instruction\$1 or cod\$3)		
<u>L3</u>	select\$4 near5 address\$3	111486	<u>L3</u>
	(activat\$4 or inactivat\$4 or inhibit\$4 or disabl\$4 or enabl\$4 or hold\$4 or held		
<u>L2</u>	or halt\$3) near6 interrupt\$3	50508	<u>L2</u>
	(activat\$4 or inactivat\$4 or inhibit\$4 or disabl\$4 or enabl\$4 or hold\$4 or		
<u>L1</u>	held) near6 interrupt\$3	48755	<u>L1</u>

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IEEE CNF IEEE Conference Proceeding

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IEEE STD IEEE Standard

- ☐
- 1. Considerations when applying ASDs in continuous processes**
Epperly, R.A.; Hoadley, F.L.; Piefer, R.W.;
Industry Applications, IEEE Transactions on
Volume 33, Issue 2, March-April 1997 Page(s):389 - 396
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(168 KB) IEEE JNL
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Lee, I.; Iyer, K.;
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7-10 Oct. 1992 Page(s):227 - 236
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